

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 106298.01		APPLICATION NO. 10/726,686	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hidemitsu ASANO et al.			
				FILING DATE December 4, 2003		GROUP 2613	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>dl</i>	1	Fang et al., "Stereo Vision and CMM Integrated Intelligent Inspection System in Reverse Engineering", PROCEEDINGS OF THE SPIE - THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, Vol. 3521, November 4, 1998, pages 115-122					
	2	Chan et al., "Neural Network Stereo Image Segmentation for Directed Coordinate Measuring Machine Part Programming", IEEE PACIFIC RIM CONFERENCE ON COMMUNICATIONS, COMPUTERS AND SIGNAL PROCESSING, August 20, 1997, pages 547-550					
<i>dl</i>	3	Wang et al., "A vision-aided alignment datum system for coordinate measuring machines", MEASUREMENT SCIENCE AND TECHNOLOGY, Vol. 8, No. 7, July 1, 1997, pages 707-714					
	4	Oltzsch et al., "Hochauflösende Bildmeßtechnik - High resolution imaging technology", TECHNISCHES MESSEN TM, Vol. 60, No. 5, May 1, 1993, pages 204-210					
<i>dl</i>	5	Wang et al., "The use of a machine vision system in a flexible manufacturing cell incorporating an automated coordinate measuring machine", PROCEEDINGS OF THE INSTITUTION OF MECHANICAL ENGINEERS, PART B, Vol. 207, No. B3, 1993, pages 199-202					
	6	Labs, "Laser sensors pay off in accuracy", I & CS - INDUSTRIAL AND PROCESS CONTROL MAGAZINE, Vol. 64, No. 7, July 1, 1991, pages 51-53					
EXAMINER <i>A. Rao</i>				DATE CONSIDERED <i>12/20/07</i>			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 106298.01		Rule 53(b) Continuation-In-Part Application of U. S. Patent Application No. 09/579,009 filed May 26, 2000	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hidemitsu ASANO et a.		GROUP	
				FILING DATE December 4, 2003			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	1	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
AL	1	6,414,711	7/2002	Arimatsu et al.	348	86	
AL	2	5,255,199	10/1993	Barkman et al.	700	175	
AL	3	5,956,253	9/1999	Gottschalk	700	186	
AL	4	6,064,759	5/2000	Buckley et al.	382	154	
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AL	5	08-014876 (w/Abstract & Translation)	1/1996	JAPAN			
AL	6	10-090284 (w/Abstract & Translation)	4/1998	JAPAN			
AL	7	08-313217 (w/Abstract & Translation)	11/1996	JAPAN			
AL	8	11-351858 (w/Abstract & Translation)	12/1999	JAPAN			
AL	9	10-078317 (w/Abstract & Translation)	03/1998	JAPAN			
	10	6-161533 (w/Abstract & Translation)	06/1994	JAPAN			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER					DATE CONSIDERED		
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